

Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from, Europe, America and south Asia, supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832

Email & Skype: info@chipsmall.com Web: www.chipsmall.com

Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China









AUTOMOTIVE GRADE

AUIRFR8401 AUIRFU8401

HEXFET® Power MOSFET

S

Source

Features

- Advanced Process Technology
- New Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- · Lead-Free, RoHS Compliant
- Automotive Qualified *

G

V _{DSS}		40V
R _{DS(on)}	typ.	$3.2 \mathrm{m}\Omega$
	max.	4.25m $Ω$
D (Silicon Lim	nited)	100A①
D (Package Li		100A

D

Drain

G

Gate

Specifically designed for Automotive applications, this HEXFET® Power MOSFETs utilizes the latest processing techniques to achieve low on-resistance per silicon area. This benefit combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in Automotive and a wide variety of other applications.

Applications

Description

- Electric Power Steering (EPS)
- · Battery Switch
- Start/Stop Micro Hybrid
- Heavy Loads
- DC-DC Converter

Daga nart number	nort number Package Type Standard Pack			Orderable Part Number
Base part number	Package Type	Form	Quantity	Orderable Part Number
AUIRFU8401	I-Pak	Tube	75	AUIRFU8401
ALUDED0404	D. Dok	Tube	75	AUIRFR8401
AUIRFR8401	D-Pak	Tape and Reel Left	3000	AUIRFR8401TRL

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	100①	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	71	
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Package Limited)	100	A
I _{DM}	Pulsed Drain Current ②	400	
P _D @T _C = 25°C	Maximum Power Dissipation	79	W
	Linear Derating Factor	0.53	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
TJ	Operating Junction and	-55 to + 175	
T_{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

Avalanche Characteristics

7.1.4.14.16.16.16.16.16.16.16.16.16.16.16.16.16.					
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) 3	67	m l		
E _{AS} (tested)	Single Pulse Avalanche Energy (Tested Limited) ®	94	mJ		
I _{AR}	Avalanche Current ②	See Fig. 14, 15, 24a, 24b	Α		
E _{AR}	Repetitive Avalanche Energy ②		mJ		

Thermal Resistance

	~			
Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		1.9	
$R_{ heta JA}$	Junction-to-Ambient (PCB Mount) ®		50	°C/W
$R_{\theta JA}$	Junction-to-Ambient		110	

HEXFET® is a registered trademark of Infineon.

^{*}Qualification standards can be found at www.infineon.com



Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	40			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.035		V/°C	Reference to 25°C, I _D = 1.0mA ③
R _{DS(on)}	Static Drain-to-Source On-Resistance		3.2	4.25	mΩ	V _{GS} = 10V, I _D = 60A ⑤
$V_{GS(th)}$	Gate Threshold Voltage	2.2		3.9	V	$V_{DS} = V_{GS}$, $I_D = 50\mu A$
	Drain-to-Source Leakage Current			1.0		$V_{DS} = 40V, V_{GS} = 0V$
I _{DSS}	Diani-to-Source Leakage Current			150	μΑ	$V_{DS} = 40V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
	Gate-to-Source Forward Leakage	_		100	- A	$V_{GS} = 20V$
I _{GSS}	Gate-to-Source Reverse Leakage			-100	nA	$V_{GS} = -20V$
R_G	Internal Gate Resistance		2.0		Ω	

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

Forward Trans conductance	198			S	$V_{DS} = 10V, I_{D} = 60A$
Total Gate Charge		42	63		$I_D = 60A$
Gate-to-Source Charge		12		20	V _{DS} = 20V
Gate-to-Drain Charge		14		110	V _{GS} = 10V ^⑤
Total Gate Charge Sync. (Q _g - Q _{gd})		28			
Turn-On Delay Time		7.9			$V_{DD} = 20V$
Rise Time		34		20	$I_D = 30A$
Turn-Off Delay Time		25		115	$R_G = 2.7\Omega$
Fall Time		24			V _{GS} = 10V⑤
Input Capacitance		2200			$V_{GS} = 0V$
Output Capacitance		340			$V_{DS} = 25V$
Reverse Transfer Capacitance		205		pF	f = 1.0MHz, See Fig. 5
Effective Output Capacitance (Energy Related)		410			V_{GS} = 0V, V_{DS} = 0V to 32V ⑦
Effective Output Capacitance (Time Related)		495			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 32V $
	Total Gate Charge Gate-to-Source Charge Gate-to-Drain Charge Total Gate Charge Sync. (Q _g - Q _{gd}) Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Input Capacitance Output Capacitance Reverse Transfer Capacitance (Energy Related)	Total Gate Charge Gate-to-Source Charge Gate-to-Drain Charge Total Gate Charge Sync. (Q _g - Q _{gd}) Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Input Capacitance Output Capacitance Reverse Transfer Capacitance (Energy Related) ———————————————————————————————————	Total Gate Charge — 42 Gate-to-Source Charge — 12 Gate-to-Drain Charge — 14 Total Gate Charge Sync. (Q _q - Q _{qd}) — 28 Turn-On Delay Time — 7.9 Rise Time — 34 Turn-Off Delay Time — 25 Fall Time — 24 Input Capacitance — 2200 Output Capacitance — 340 Reverse Transfer Capacitance — 205 Effective Output Capacitance (Energy Related) — 410	Total Gate Charge — 42 63 Gate-to-Source Charge — 12 — Gate-to-Drain Charge — 14 — Total Gate Charge Sync. (Qg - Qgd) — 28 — Turn-On Delay Time — 7.9 — Rise Time — 34 — Turn-Off Delay Time — 25 — Fall Time — 24 — Input Capacitance — 2200 — Output Capacitance — 340 — Reverse Transfer Capacitance — 205 — Effective Output Capacitance (Energy Related) — 410 —	Total Gate Charge — 42 63 Gate-to-Source Charge — 12 — Gate-to-Drain Charge — 14 — Total Gate Charge Sync. (Qg - Qgd) — 28 — Turn-On Delay Time — 7.9 — Rise Time — 34 — Turn-Off Delay Time — 25 — Fall Time — 24 — Input Capacitance — 2200 — Output Capacitance — 340 — Reverse Transfer Capacitance — 205 — Effective Output Capacitance (Energy Related) — 410 —

Diode Characteristics

	1					T
	Parameter	Min.	Тур.	Max.	Units	Conditions
	Continuous Source Current			1000		MOSFET symbol
Is	(Body Diode)			100 ^①	_	showing the
	Pulsed Source Current			400	Α	integral reverse
I _{SM}	(Body Diode) ①			400		p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 60A, V_{GS} = 0V $ §
dv/dt	Peak Diode Recovery dv/dt@		3.2		V/ns	$T_J = 175^{\circ}C, I_S = 60A, V_{DS} = 40V $
t _{rr}	Reverse Recovery Time		28		no	$T_J = 25^{\circ}C$ $V_R = 34V$,
			29		ns	$T_J = 125^{\circ}C$ $I_F = 60A$
Q_{rr}	Reverse Recovery Charge		28		nC	$T_J = 25^{\circ}C$ di/dt = 100A/µs ©
			31		IIIC	T _J = 125°C di/dt = 100A/μs ⑤
I _{RRM}	Reverse Recovery Current		1.6		Α	T _J = 25°C

Notes:

- ① Calculated continuous current based on maximum allowable junction temperature. Bond wire current limit is 100A by source bonding technology. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements. (Refer to AN-1140)
- ② Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ③ Limited by T_{Jmax} , starting $T_J = 25$ °C, L = 0.037mH, $R_G = 50\Omega$, $I_{AS} = 60$ A, $V_{GS} = 10$ V.
- ⑤ Pulse width $\leq 400 \mu s$; duty cycle $\leq 2\%$.
- \odot Coss eff. (TR) is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .
- © C_{oss eff}. (ER) is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994
- \mathfrak{G} R_θ is measured at T_J approximately 90°C.
- \odot This value determined from sample failure population, starting T_J = 25°C, L=0.037mH, R_G = 25Ω, I_{AS} = 60A, V_{GS} =10V



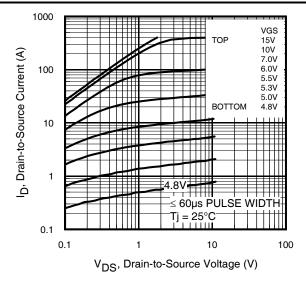


Fig. 1 Typical Output Characteristics

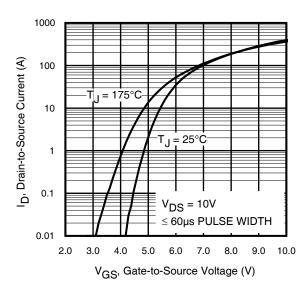


Fig. 3 Typical Transfer Characteristics

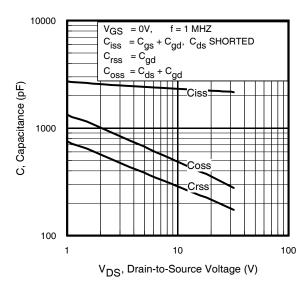


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

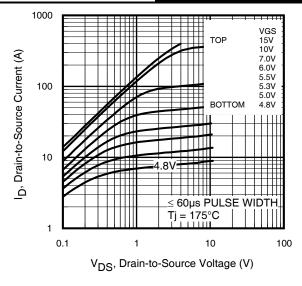


Fig. 2 Typical Output Characteristics

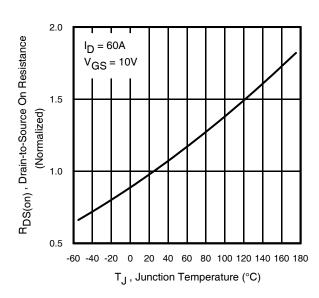


Fig. 4 Normalized On-Resistance vs. Temperature

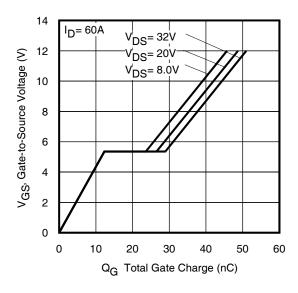


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage



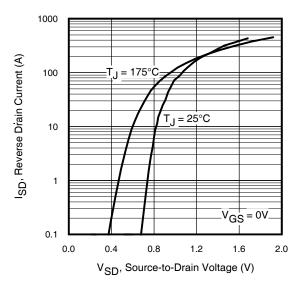


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

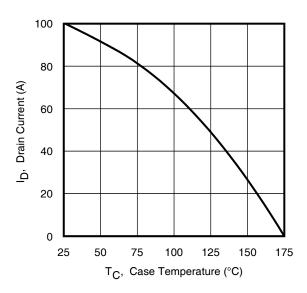


Fig. 9 Maximum Drain Current vs. Case Temperature

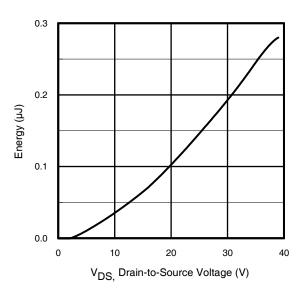


Fig. 11 Typical Coss Stored Energy

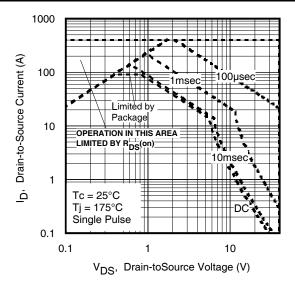


Fig 8. Maximum Safe Operating Area

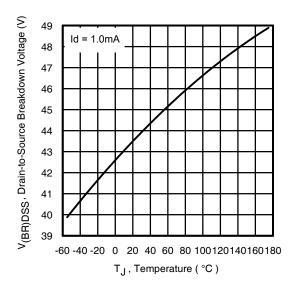


Fig 10. Drain-to-Source Breakdown Voltage

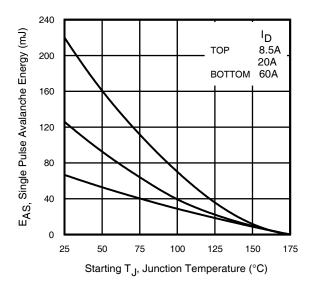


Fig 12. Maximum Avalanche Energy vs. Drain Current



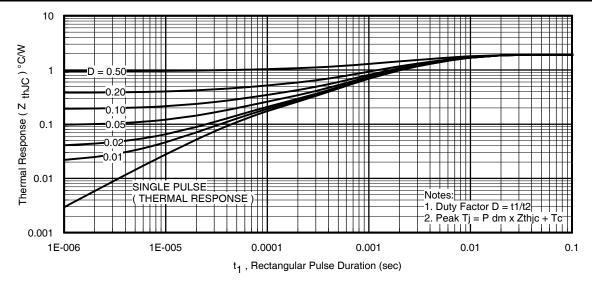


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

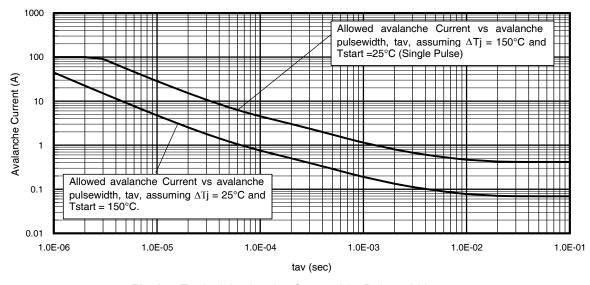


Fig 14. Typical Avalanche Current Vs. Pulse width

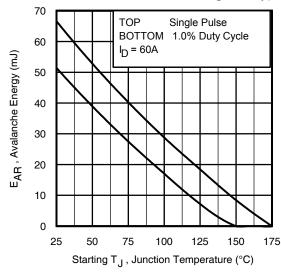


Fig 15. Maximum Avalanche Energy Vs. Temperature

Notes on Repetitive Avalanche Curves, Figures 14, 15: (For further info, see AN-1005 at www.infineon.com)

- Avalanche failures assumption:
 Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax}. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as T_{jmax} is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 22a, 22b.
- 4. PD (ave) = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. lav = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 13, 14).

tav = Average time in avalanche.

D = Duty cycle in avalanche = tav ·f

ZthJC(D, tav) = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \text{ (ave)}} &= 1/2 \text{ (} 1.3 \cdot \text{BV} \cdot \text{I}_{av} \text{)} = \Delta \text{T} / \text{Z}_{thJC} \\ I_{av} &= 2\Delta \text{T} / \text{ [} 1.3 \cdot \text{BV} \cdot \text{Z}_{th} \text{]} \\ E_{AS \text{ (AR)}} &= P_{D \text{ (ave)}} \cdot t_{av} \end{split}$$



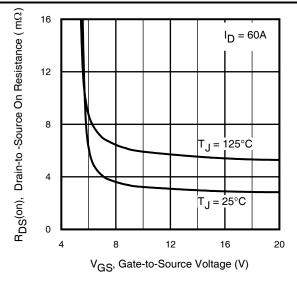


Fig 16. On-Resistance vs. Gate Voltage

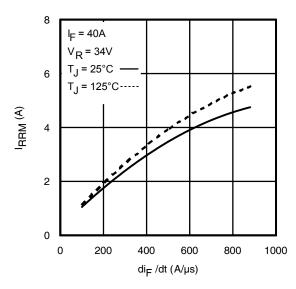


Fig. 18 - Typical Recovery Current vs. dif/dt

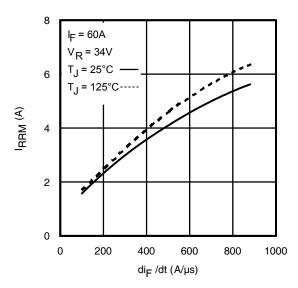


Fig. 20 - Typical Recovery Current vs. dif/dt

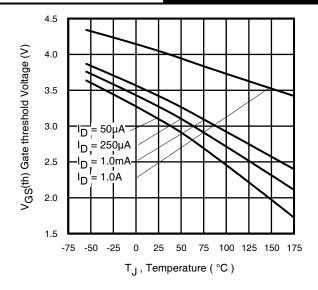


Fig. 17 - Threshold Voltage vs. Temperature

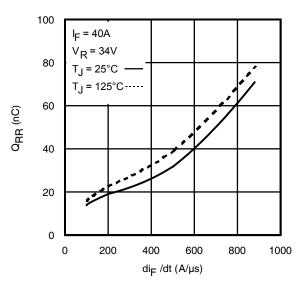


Fig. 19 - Typical Stored Charge vs. dif/dt

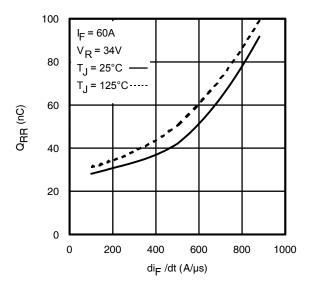


Fig. 21 - Typical Stored Charge vs. dif/dt

2016-1-28



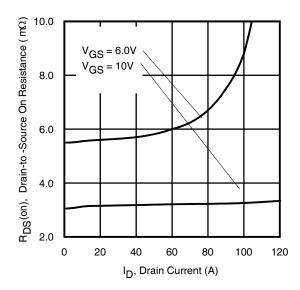


Fig 22. Typical On-Resistance vs. Drain Current

2016-1-28



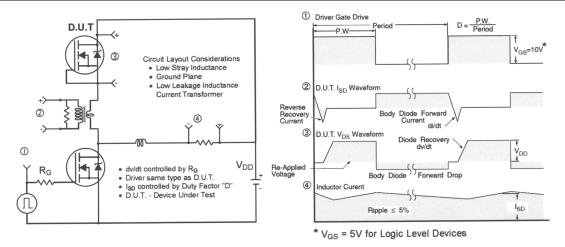


Fig 23. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

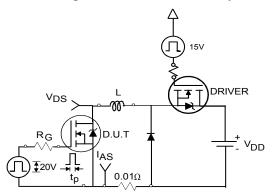


Fig 24a. Unclamped Inductive Test Circuit

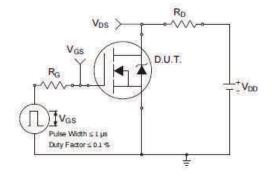


Fig 25a. Switching Time Test Circuit

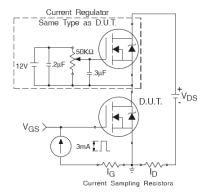


Fig 26a. Gate Charge Test Circuit

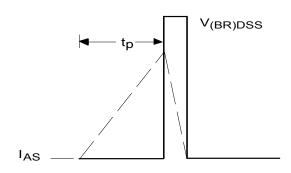


Fig 24b. Unclamped Inductive Waveforms

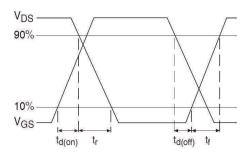


Fig 25b. Switching Time Waveforms

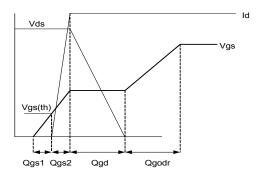
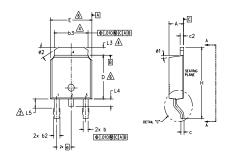


Fig 26b. Gate Charge Waveform

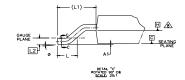
8

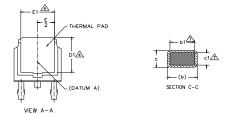


D-Pak (TO-252AA) Package Outline (Dimensions are shown in millimeters (inches))









NOTES:

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- LEAD DIMENSION UNCONTROLLED IN L5.
- A- DIMENSION D1, E1, L3 & b3 ESTABLISH A MINIMUM MOUNTING SURFACE FOR THERMAL PAD.
- 5.— SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 AND 0.10 [0.13 AND 0.25] FROM THE LEAD TIP.
- bildension D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- A- DIMENSION b1 & c1 APPLIED TO BASE METAL ONLY.
- ♠ DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 9.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-252AA.

S		DIMEN			
Y M		N			
B	MILLIM	ETERS	INC	HES	O T E S
L	MIN.	MAX.	MIN.	MAX.	S
Α	2.18	2.39	.086	.094	
A1	-	0.13	-	.005	
b	0.64	0.89	.025	.035	
ь1	0.65	0.79	.025	.031	7
b2	0.76	1.14	.030	.045	
b3	4.95	5.46	.195	.215	4
С	0.46	0.61	.018	.024	
c1	0.41	0.56	.016	.022	7
c2	0.46	0.89	.018	.035	
D	5.97	6.22	.235	.245	6
D1	5.21	-	.205	-	4
Ε	6.35	6.73	.250	.265	6
E1	4.32	-	.170	-	4
е	2.29	BSC	.090	BSC	
Н	9.40	10.41	.370	.410	
L	1.40	1.78	.055	.070	
L1	2.74	BSC	.108	REF.	
L2	0.51	BSC	.020	.020 BSC	
L3	0.89	1.27	.035	.050	4
L4	-	1.02	-	.040	
L5	1.14	1.52	.045	.060	3
ø	0,	10*	0,	10°	
ø1	0,	15*	0.	15*	
ø2	25*	35°	25*	35*	

LEAD ASSIGNMENTS

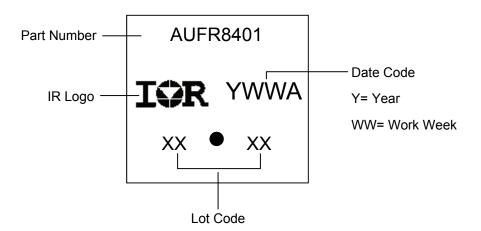
HEXFET

- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE
- 4.- DRAIN

IGBT & CoPAK

- 1.- GATE
- 2.- COLLECTOR
- 3.- EMITTER
- 4.- COLLECTOR

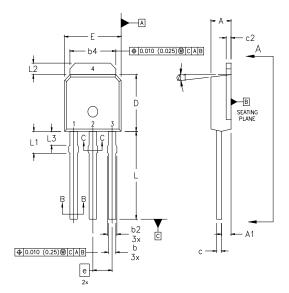
D-Pak (TO-252AA) Part Marking Information

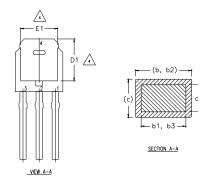


Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



I-Pak (TO-251AA) Package Outline (Dimensions are shown in millimeters (inches)





NOTES:

- 1 DIMENSIONING AND TOLERANCING PER ASME Y14.5 M- 1994.
- 2 DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 3 DIMENSION D & E DO NOT INCLUDE MOLD FLASH, MOLD FLASH SHALL NOT EXCEED 0.005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 4 THERMAL PAD CONTOUR OPTION WITHIN DIMENSION 64, L2, E1 & D1.
 - LEAD DIMENSION UNCONTROLLED IN L3.
- 6 DIMENSION 61, 63 APPLY TO BASE METAL ONLY.
 - OUTLINE CONFORMS TO JEDEC OUTLINE TO-251AA.

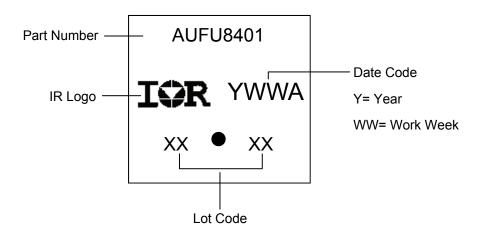
8 CONTROLLING DIMENSION : INCHES.

LEAD ASSIGNMENTS

н	Ŀ۷	X٢	Ŀ	П

- 1.- GATE 2.- DRAIN
- 3.- SOURCE 4.- DRAIN
- DIMENSIONS SYMBOL MILLIMETERS INCHES MIN. NOTES 2.18 2.39 0.086 .094 A1 0.89 1.14 0.035 0.045 b 0.64 0.89 0.025 0.035 ь1 0.64 0.79 0.025 0.031 b2 0.76 1.14 0.030 0.045 0.76 1.04 0.030 0.041 5.00 5.46 0.195 0.215 b4 0.46 0.61 0.018 0.024 0.016 0.41 0.56 0.022 c1 c2 .046 0.86 0.018 0.035 D 5.97 6.22 0.235 0.245 D1 5.21 0.205 6.35 6.73 0.250 0.265 E1 4.32 0.170 0.090 BSC е L 8.89 9.60 0.350 0.380 L1 1,91 2.29 0.075 0.090 L2 0.89 1.27 0.035 0.050 L3 1.14 1.52 0.045 0.060 15*

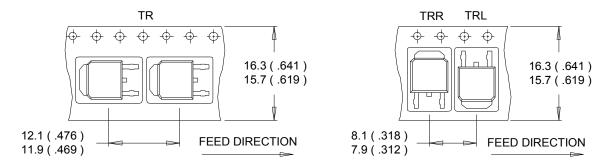
I-Pak (TO-251AA) Part Marking Information



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

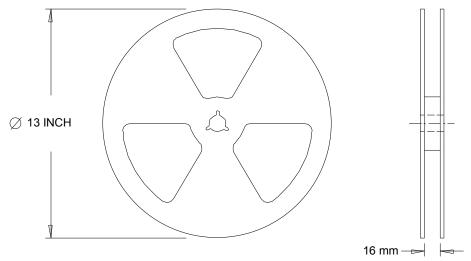


D-Pak (TO-252AA) Tape & Reel Information (Dimensions are shown in millimeters (inches))



NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETER.
- 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
- 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES:

1. OUTLINE CONFORMS TO EIA-481.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



Qualification Information

	ion imorniación					
		Automotive				
		(per AEC-Q101)				
Qualificat	ion Level	Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the highe Automotive level.				
Moisture Sensitivity Level		D-Pak	MSL1			
		I-Pak	IVISL I			
	Machine Model	Class M2 (+/- 200V) [†]				
	Macrime Moder	AEC-Q101-002				
FOD	Liveran Dady Madal	Class H1B (+/- 1000V) [†]				
E9D	Human Body Model		AEC-Q101-001			
			Class C5 (+/- 2000V) [†]			
Charged Device Model		AEC-Q101-005				
RoHS Compliant		Yes				

[†] Highest passing voltage.

Revision History

Date	Comments				
12/14/2015	 Updated datasheet with corporate template Corrected ordering table on page 1. 				
1/28/2016	Corrected Qualification table (Human Body model value) on page 12.				

Published by Infineon Technologies AG 81726 München, Germany © Infineon Technologies AG 2015 All Rights Reserved.

IMPORTANT NOTICE

The information given in this document shall in <u>no event</u> be regarded as a guarantee of conditions or characteristics ("Beschaffenheitsgarantie"). With respect to any examples, hints or any typical values stated herein and/or any information regarding the application of the product, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation warranties of non-infringement of intellectual property rights of any third party.

In addition, any information given in this document is subject to customer's compliance with its obligations stated in this document and any applicable legal requirements, norms and standards concerning customer's products and any use of the product of Infineon Technologies in customer's applications.

The data contained in this document is exclusively intended for technically trained staff. It is the responsibility of customer's technical departments to evaluate the suitability of the product for the intended application and the completeness of the product information given in this document with respect to such application.

For further information on the product, technology, delivery terms and conditions and prices please contact your nearest Infineon Technologies office (www.infineon.com).

WARNINGS

Due to technical requirements products may contain dangerous substances. For information on the types in question please contact your nearest Infineon Technologies office.

Except as otherwise explicitly approved by Infineon Technologies in a written document signed by authorized representatives of Infineon Technologies, Infineon Technologies' products may <u>not</u> be used in any applications where a failure of the product or any consequences of the use thereof can reasonably be expected to result in personal injury.